

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In Re: Wenbing Yun *et al.* Confirmation No: 7844  
Application No: 10/683,872 Group: 2872  
Filed: October 10, 2003 Examiner: Assaf, Faye G.  
For: Short Wavelength Metrology  
Imaging System  
Customer No.: 29127

Attorney Docket No.	0002.0004.us
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**AMENDMENT UNDER RULE 111**

**Commissioner for Patents**  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:  
In response to the pending Office Action, mailed December 27, 2006 (Paper No. 20061233), please amend the above-captioned application as follows:

-amendments to the specification are set forth in section a);

-amendments to the claims are reflected in the listing of claims in section b); and

Finally, reconsideration is requested in view of the remarks set forth in section c).